

# IRF7805

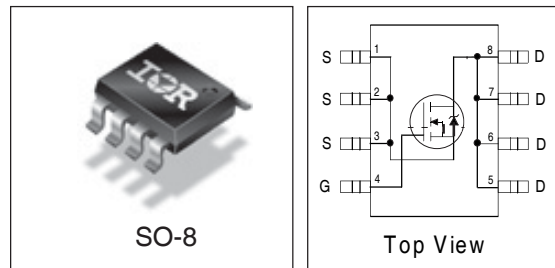
## HEXFET® Chip-Set for DC-DC Converters

- N Channel Application Specific MOSFETs
- Ideal for Mobile DC-DC Converters
- Low Conduction Losses
- Low Switching Losses

### Description

This new device employs advanced HEXFET Power MOSFET technology to achieve an unprecedented balance of on-resistance and gate charge. The reduced conduction and switching losses make this device ideal for high efficiency DC-DC Converters that power the latest generation of mobile microprocessors.

The IRF7805 offers maximum efficiency for mobile CPU core DC-DC converters.



### Device Features

	IRF7805
$V_{DS}$	30V
$R_{DS(on)}$	11m $\Omega$
$Q_g$	31nC
$Q_{sw}$	11.5nC
$Q_{oss}$	36nC

### Absolute Maximum Ratings

	Parameter	Max.	Units
$V_{DS}$	Drain-to-Source Voltage	30	V
$V_{GS}$	Gate-to-Source Voltage	$\pm 12$	
$I_D @ T_A = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$ ③	13	A
$I_D @ T_A = 70^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$ ③	10	
$I_{DM}$	Pulsed Drain Current ①	100	
$P_D @ T_A = 25^\circ\text{C}$	Power Dissipation ③	2.5	W
$P_D @ T_A = 70^\circ\text{C}$	Power Dissipation ③	1.6	
	Linear Derating Factor	0.02	W/ $^\circ\text{C}$
$T_J$	Operating Junction and	-55 to + 150	$^\circ\text{C}$
$T_{STG}$	Storage Temperature Range		

### Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JL}$	Junction-to-Drain Lead ⑤	—	20	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Junction-to-Ambient ③⑤	—	50	

## Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{DSS}$	Drain-to-Source Breakdown Voltage <sup>⑥</sup>	30	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$R_{DS(on)}$	Static Drain-to-Source On-Resistance <sup>⑥</sup>	—	9.2	11	m $\Omega$	$V_{GS} = 4.5V, I_D = 7.0A$ <sup>②</sup>
$V_{GS(th)}$	Gate Threshold Voltage <sup>⑥</sup>	1.0	—	3.0	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	70	$\mu A$	$V_{DS} = 30V, V_{GS} = 0V$
		—	—	10		$V_{DS} = 24V, V_{GS} = 0V$
		—	—	150		$V_{DS} = 24V, V_{GS} = 0V, T_J = 100^\circ C$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 12V$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS} = -12V$
$Q_g$	Total Gate Charge <sup>⑥</sup>	—	22	31	nC	$V_{GS} = 5.0V$ $V_{DS} = 16V$ $I_D = 7.0A$
$Q_{gs1}$	Pre-V <sub>th</sub> Gate-to-Source Charge	—	3.7	—		
$Q_{gs2}$	Post-V <sub>th</sub> Gate-to-Source Charge	—	1.4	—		
$Q_{gd}$	Gate-to-Drain Charge	—	6.8	—		
$Q_{sw}$	Switch Charge ( $Q_{gs2} + Q_{gd}$ ) <sup>⑥</sup>	—	8.2	11.5		
$Q_{oss}$	Output Charge <sup>⑥</sup>	—	3.0	3.6	nC	$V_{DS} = 16V, V_{GS} = 0V$
$R_G$	Gate Resistance	0.5	—	1.7	$\Omega$	
$t_{d(on)}$	Turn-On Delay Time	—	16	—	ns	$V_{DD} = 16V, V_{GS} = 4.5V$ <sup>③</sup> $I_D = 7.0A$ $R_G = 2\Omega$ Resistive Load
$t_r$	Rise Time	—	20	—		
$t_{d(off)}$	Turn-Off Delay Time	—	38	—		
$t_f$	Fall Time	—	16	—		

## Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode) <sup>①</sup>	—	—	2.5	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode)	—	—	106		
$V_{SD}$	Diode Forward Voltage <sup>⑥</sup>	—	—	1.2	V	$T_J = 25^\circ C, I_S = 7.0A, V_{GS} = 0V$
$Q_{rr}$	Reverse Recovery Charge <sup>④</sup>	—	88	—	ns	$di/dt = 700A/\mu s$ $V_{DS} = 16V, V_{GS} = 0V, I_S = 7.0A$
$Q_{rr(s)}$	Reverse Recovery Charge (with Parallel Schottky) <sup>④</sup>	—	55	—	nC	$di/dt = 700A/\mu s$ (with 10BQ040) $V_{DS} = 16V, V_{GS} = 0V, I_S = 7.0A$

### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Pulse width  $\leq 300 \mu s$ ; duty cycle  $\leq 2\%$ .
- ③ When mounted on 1 inch square copper board,  $t < 10$  sec.
- ④ Typ = measured -  $Q_{oss}$ .
- ⑤  $R_\theta$  is measured at  $T_J$  of approximately  $90^\circ C$ .
- ⑥ Devices are 100% tested to these parameters.

Typical Characteristics

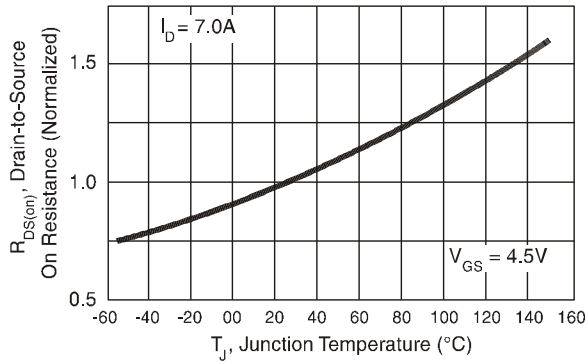


Fig 1. Normalized On-Resistance vs. Temperature

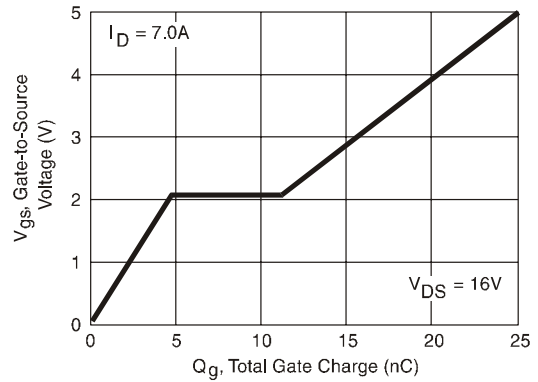


Fig 2. Typical Gate Charge vs. Gate-to-Source Voltage

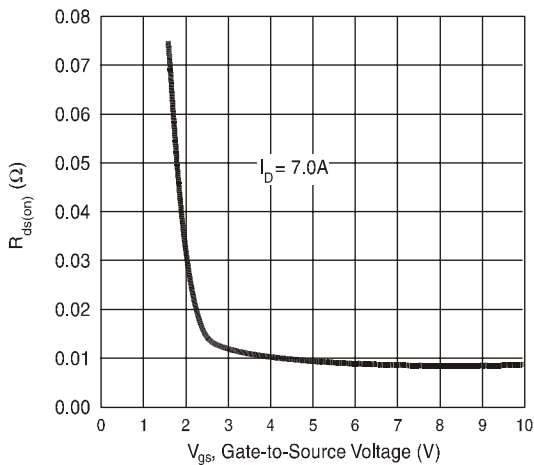


Fig 3. Typical  $R_{DS(on)}$  vs. Gate-to-Source Voltage

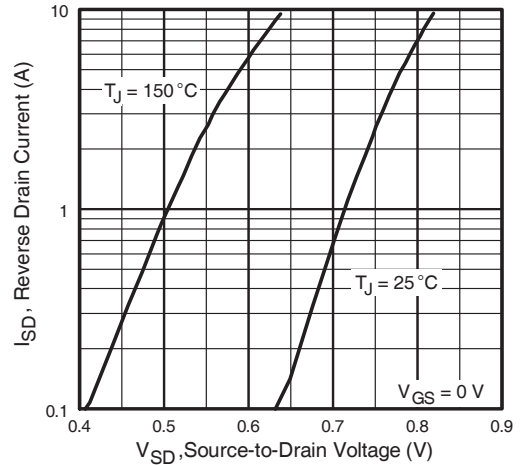


Fig 4. Typical Source-Drain Diode Forward Voltage

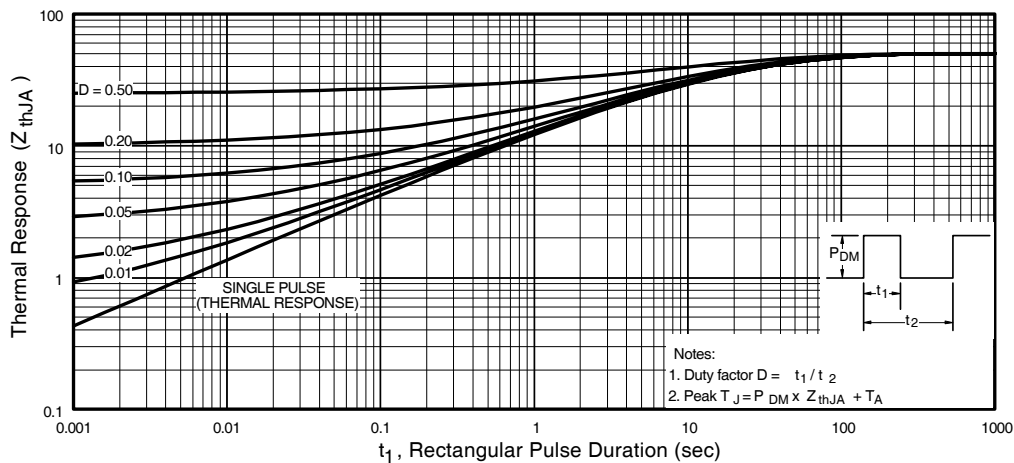


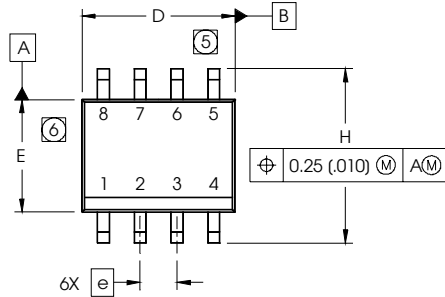
Figure 5. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

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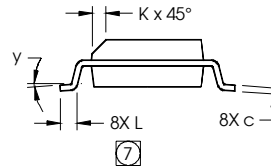
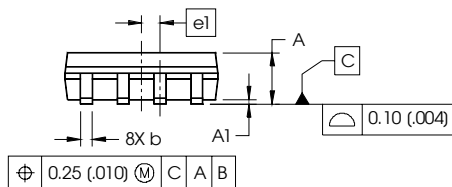
International  
**IR** Rectifier

## SO-8 Package Details

Dimensions are shown in millimeters (inches)



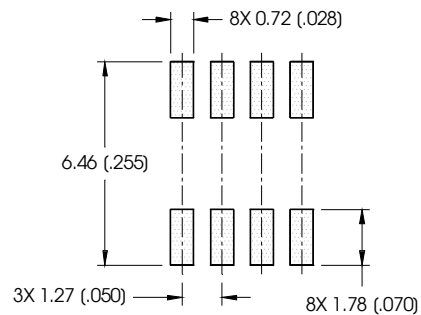
DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
b	.013	.020	0.33	0.51
c	.0075	.0098	0.19	0.25
D	.189	.1968	4.80	5.00
E	.1497	.1574	3.80	4.00
e	.050 BASIC		1.27 BASIC	
e1	.025 BASIC		0.635 BASIC	
H	.2284	.2440	5.80	6.20
K	.0099	.0196	0.25	0.50
L	.016	.050	0.40	1.27
y	0°	8°	0°	8°



### NOTES:

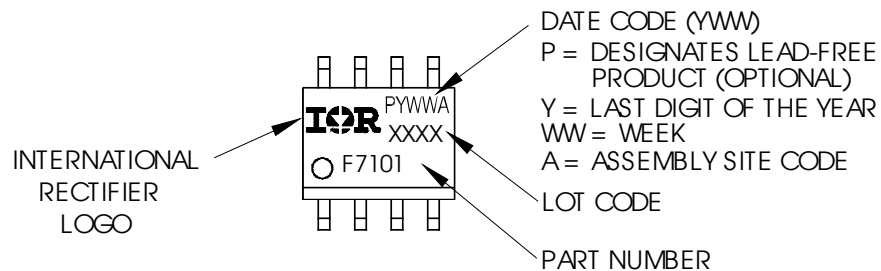
1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
2. CONTROLLING DIMENSION: MILLIMETER
3. DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA
5. DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.15 (.006).
6. DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.25 (.010).
7. DIMENSION IS THE LENGTH OF LEAD FOR SOLDERING TO SUBSTRATE.

### FOOTPRINT

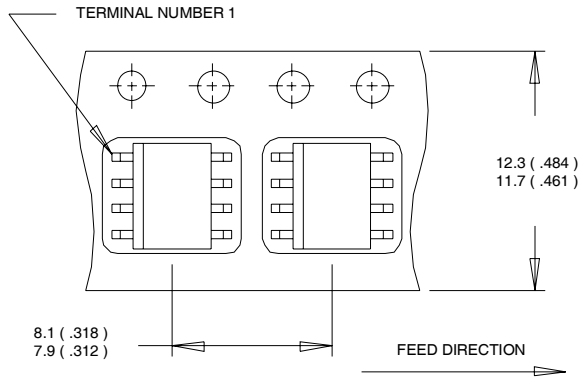


## SO-8 Part Marking

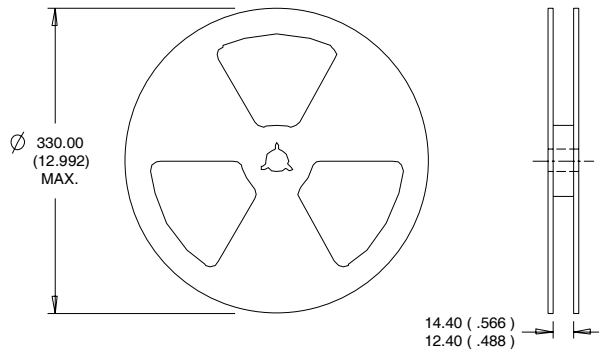
EXAMPLE: THIS IS AN IRF7101 (MOSFET)



**SO-8 Tape and Reel**



- NOTES:
1. CONTROLLING DIMENSION : MILLIMETER.
  2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
  3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



- NOTES :
1. CONTROLLING DIMENSION : MILLIMETER.
  2. OUTLINE CONFORMS TO EIA-481 & EIA-541.